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1 Overview

This document contains information for TPS62160-Q1 and TPS62162-Q1 (WSON package) to aid in a functional safety system design. Information provided are:

- Functional Safety Failure In Time (FIT) rates of the semiconductor component estimated by the application of industry reliability standards
- Component failure modes and their distribution (FMD) based on the primary function of the device
- Pin failure mode analysis (Pin FMA)

Figure 1-2 shows the device functional block diagram for reference.

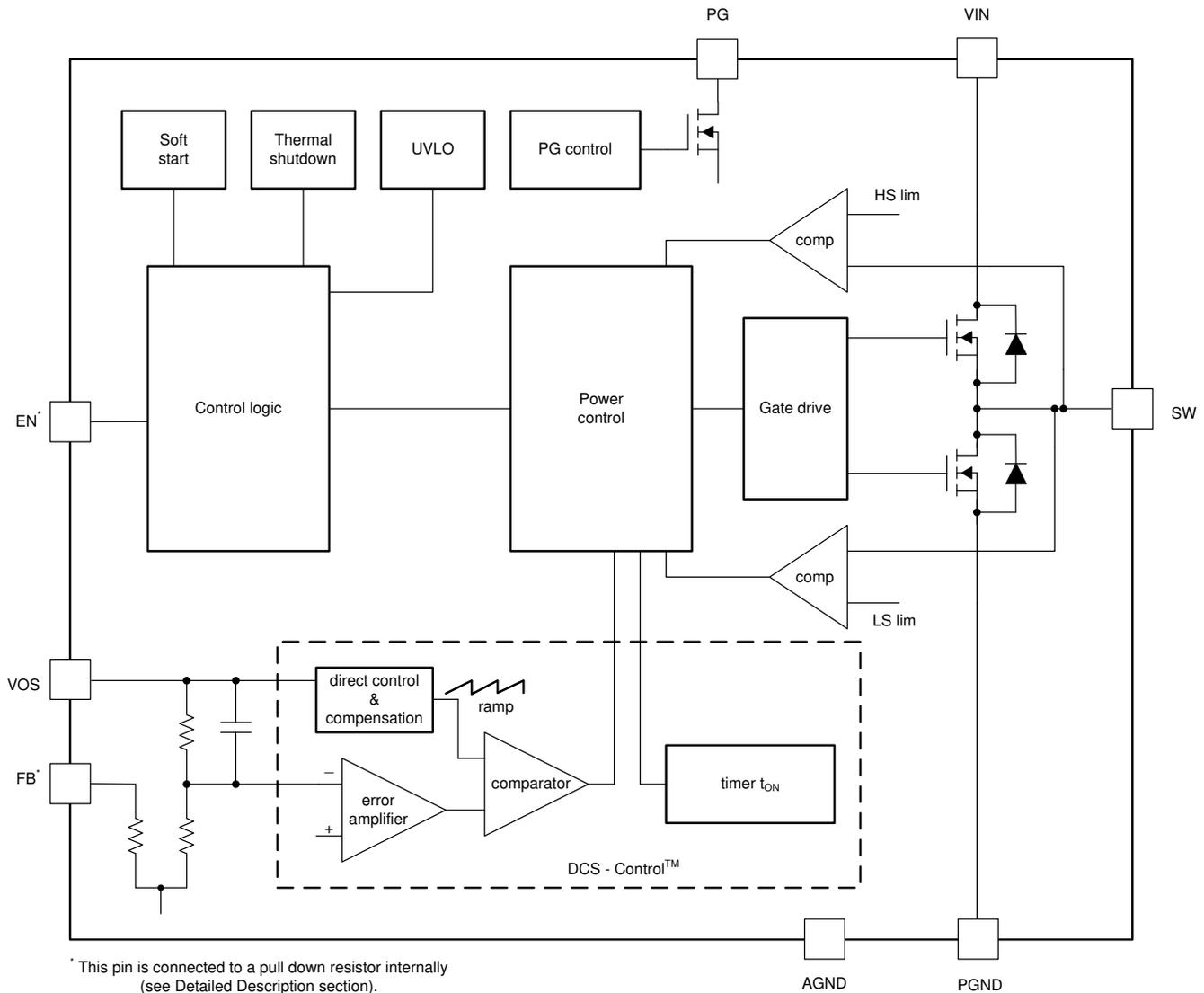


Figure 1-1. TPS62162-Q1 Functional Block Diagram

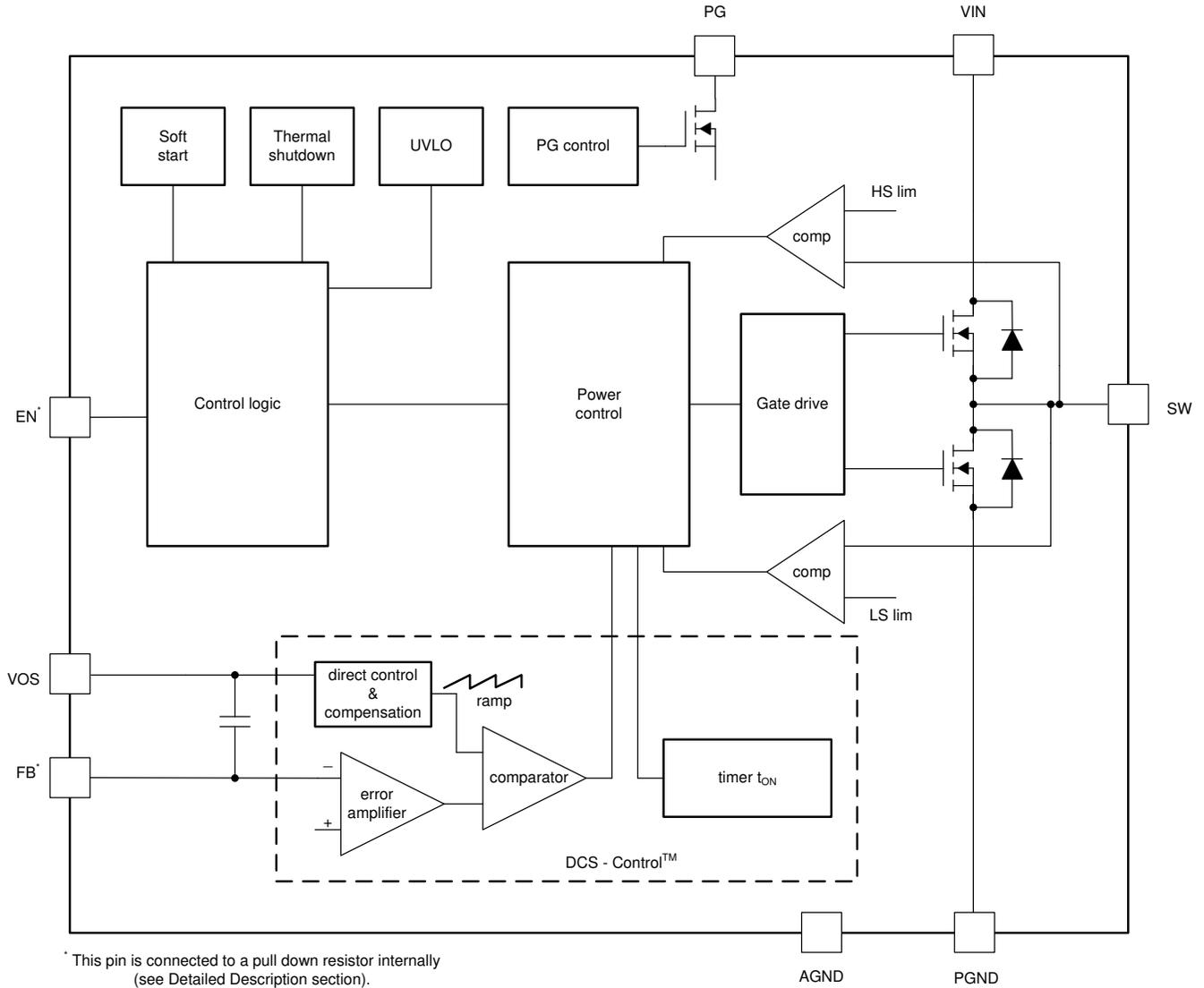


Figure 1-2. TPS62160-Q1 Functional Block Diagram

TPS62160-Q1 and TPS62162-Q1 were developed using a quality-managed development process, but were not developed in accordance with the IEC 61508 or ISO 26262 standards.

2 Functional Safety Failure In Time (FIT) Rates

This section provides Functional Safety Failure In Time (FIT) rates for TPS62160-Q1 and TPS62162-Q1 based on two different industry-wide used reliability standards:

- [Table 2-1](#) provides FIT rates based on IEC TR 62380 / ISO 26262 part 11
- [Table 2-2](#) provides FIT rates based on the Siemens Norm SN 29500-2

Table 2-1. Component Failure Rates per IEC TR 62380 / ISO 26262 Part 11

FIT IEC TR 62380 / ISO 26262	FIT (Failures Per 10 ⁹ Hours)
Total Component FIT Rate	9
Die FIT Rate	7
Package FIT Rate	2

The failure rate and mission profile information in [Table 2-1](#) comes from the Reliability data handbook IEC TR 62380 / ISO 26262 part 11:

- Mission Profile: Motor Control from Table 11
- Power dissipation: 500 mW
- Climate type: World-wide Table 8
- Package factor (lambda 3): Table 17b
- Substrate Material: FR4
- EOS FIT rate assumed: 0 FIT

Table 2-2. Component Failure Rates per Siemens Norm SN 29500-2

Table	Category	Reference FIT Rate	Reference Virtual T _J
5	CMOS/BICMOS ASICs Analog & Mixed < 50V supply	25	55°C

The Reference FIT Rate and Reference Virtual T_J (junction temperature) in [Table 2-2](#) come from the Siemens Norm SN 29500-2 tables 1 through 5. Failure rates under operating conditions are calculated from the reference failure rate and virtual junction temperature using conversion information in SN 29500-2 section 4.

3 Failure Mode Distribution (FMD)

The failure mode distribution estimation for TPS62160-Q1 and TPS62162-Q1 in [Table 3-1](#) comes from the combination of common failure modes listed in standards such as IEC 61508 and ISO 26262, the ratio of sub-circuit function size and complexity and from best engineering judgment.

The failure modes listed in this section reflect random failure events and do not include failures due to misuse or overstress.

Table 3-1. Die Failure Modes and Distribution

Die Failure Modes	Failure Mode Distribution (%)
SW no output	35%
SW output not in specification – voltage or timing	45%
SW power HS or LS FET stuck on	10%
PG false trip, fails to trip	5%
Short circuit any two pins	5%

The FMD in [Table 3-1](#) excludes short circuit faults across the isolation barrier. Faults for short circuit across the isolation barrier can be excluded according to ISO 61800-5-2:2016 if the following requirements are fulfilled:

1. The signal isolation component is OVC III according to IEC 61800-5-1. If a SELV/PELV power supply is used, pollution degree 2/OVC II applies. All requirements of IEC 61800-5-1:2007, 4.3.6 apply.
2. Measures are taken to ensure that an internal failure of the signal isolation component cannot result in excessive temperature of its insulating material.

Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed-circuit board do not reduce this distance.

4 Pin Failure Mode Analysis (Pin FMA)

This section provides a Failure Mode Analysis (FMA) for the pins of the TPS62160-Q1 and TPS62162-Q1. The failure modes covered in this document include the typical pin-by-pin failure scenarios:

- Pin short-circuited to Ground (see [Table 4-2](#) and [Table 4-6](#))
- Pin open-circuited (see [Table 4-3](#) and [Table 4-7](#))
- Pin short-circuited to an adjacent pin (see [Table 4-4](#) and [Table 4-8](#))
- Pin short-circuited to supply (see [Table 4-5](#) and [Table 4-9](#))

The following tables also indicate how these pin conditions can affect the device as per the failure effects classification in [Table 4-1](#).

Table 4-1. TI Classification of Failure Effects

Class	Failure Effects
A	Potential device damage that affects functionality
B	No device damage, but loss of functionality
C	No device damage, but performance degradation
D	No device damage, no impact to functionality or performance

[Figure 4-1](#) shows the TPS62160-Q1 and TPS62162-Q1 pin diagram. For a detailed description of the device pins please refer to the *Pin Configuration and Functions* section in the TPS62160-Q1 and TPS62162-Q1 data sheet.

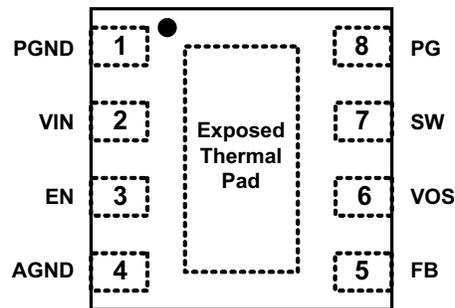


Figure 4-1. Pin Diagram

4.1 Pin Failure Mode Analysis for TPS62160-Q1

Table 4-2. Pin FMA for TPS62160-Q1 Pins Short-Circuited to Ground

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
PGND	1	No effect	D
VIN	2	Device does not power up	B
EN	3	Device does not power up	B
AGND	4	No effect	D
FB	5	Loss of VOUT regulation	B
VOS	6	Loss of VOUT regulation	B
SW	7	Potential device damage	A
PG	8	Loss of power good Indication	C

Table 4-3. Pin FMA for TPS62160-Q1 Pins Open-Circuited

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
PGND	1	Output regulation normal, potential impact to reliability of power FETs	C
VIN	2	Device does not power up	B
EN	3	Device does not power up	B
AGND	4	Output regulation normal, potential noise issues/jitter	C
FB	5	Open loop operation, Undetermined output voltage behavior	B
VOS	6	Open loop operation, Undetermined output voltage behavior	B
SW	7	Device not functional	B
PG	8	Loss of power good indication	C

Table 4-4. Pin FMA for TPS62160-Q1 Pins Short-Circuited to Adjacent Pin

Pin Name	Pin No.	Shorted to	Description of Potential Failure Effect(s)	Failure Effect Class
PGND	1	VIN	No output voltage	B
VIN	2	EN	Normal Operation	D
EN	3	AGND	No output voltage	B
FB	5	VOS	Loss of VOUT regulation	B
VOS	6	SW	Device Damage	A
SW	7	PG	Device Damage	A

Table 4-5. Pin FMA for TPS62160-Q1 Pins Short-Circuited to Supply

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
PGND	1	No output voltage	B
VIN	2	Normal Operation	D
EN	3	Normal Operation	D
AGND	4	No output voltage	B
FB	5	Possible device damage ⁽¹⁾ : Abs max may be exceeded Loss of VOUT regulation	A
VOS	6	Possible device damage ⁽¹⁾ : Abs max may be exceeded Loss of VOUT regulation	A
SW	7	Device damage	A
PG	8	Possible device damage ⁽¹⁾ : Abs max may be exceeded	A

(1) Damage will occur if Vin is greater than the 7-V Absolute Maximum Rating for the pin.

4.2 Pin Failure Mode Analysis for TPS62162-Q1

Table 4-6. Pin FMA for TPS62162-Q1 Pins Short-Circuited to Ground

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
PGND	1	No effect	D
VIN	2	Device does not power up	B
EN	3	Device does not power up	B
AGND	4	No effect	D
FB	5	No effect	D
VOS	6	Loss of VOUT regulation	B
SW	7	Potential device damage	A
PG	8	Loss of power good Indication	C

Table 4-7. Pin FMA for TPS62162-Q1 Pins Open-Circuited

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
PGND	1	Output regulation normal, potential impact to reliability of power FETs	C
VIN	2	Device does not power up	B
EN	3	Device does not power up	B
AGND	4	Output regulation normal, potential noise issues/jitter	C
FB	5	No effect	D
VOS	6	Open loop operation, Undetermined output voltage behavior	B
SW	7	Device not functional	B
PG	8	Loss of power good indication	C

Table 4-8. Pin FMA for TPS62162-Q1 Pins Short-Circuited to Adjacent Pin

Pin Name	Pin No.	Shorted to	Description of Potential Failure Effect(s)	Failure Effect Class
PGND	1	VIN	No output voltage	B
VIN	2	EN	Normal Operation	D
EN	3	AGND	No output voltage	B
FB	5	VOS	Loss of VOUT regulation	B
VOS	6	SW	Device Damage	A
SW	7	PG	Device Damage	A

Table 4-9. Pin FMA for TPS62162-Q1 Pins Short-Circuited to Supply

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
PGND	1	No output voltage	B
VIN	2	Normal Operation	D
EN	3	Normal Operation	D
AGND	4	No output voltage	B
FB	5	Possible device damage ⁽¹⁾ : Abs max may be exceeded Loss of VOUT regulation	A
VOS	6	Possible device damage ⁽¹⁾ : Abs max may be exceeded Loss of VOUT regulation	A
SW	7	Device damage	A
PG	8	Possible device damage ⁽¹⁾ : Abs max may be exceeded	A

(1) Damage will occur if Vin is greater than the 7-V Absolute Maximum Rating for the pin.

5 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (December 2019) to Revision A (November 2020)	Page
• Updated using new template.....	2
• Added Pin FMA.....	8

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